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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	Coldfire V4
Core Size	32-Bit Single-Core
Speed	180MHz
Connectivity	I ² C, SPI, SSI, UART/USART, USB OTG
Peripherals	DMA, WDT
Number of I/O	132
Program Memory Size	-
Program Memory Type	ROMless
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.35V ~ 3.6V
Data Converters	-
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	256-LBGA
Supplier Device Package	256-MAPBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mcf54450cvm180

1 MCF5445x Family Comparison

The following table compares the various device derivatives available within the MCF5445x family.

Table 1. MCF5445x Family Configurations

Module	MCF54450	MCF54451	MCF54452	MCF54453	MCF54454	MCF54455
ColdFire Version 4 Core with EMAC (Enhanced Multiply-Accumulate Unit)	•	•	•	•	•	•
Core (System) Clock	up to 240 MHz		up to 266 MHz			
Peripheral Bus Clock (Core clock ÷ 2)	up to 120 MHz		up to 133 MHz			
External Bus Clock (Core clock ÷ 4)	up to 60 MHz		up to 66 MHz			
Performance (Dhrystone/2.1 MIPS)	up to 370		up to 410			
Independent Data/Instruction Cache	16 Kbytes each					
Static RAM (SRAM)	32 Kbytes					
PCI Controller	—	—	•	•	•	•
Cryptography Acceleration Unit (CAU)	—	•	—	•	—	•
ATA Controller	—	—	—	—	•	•
DDR SDRAM Controller	•	•	•	•	•	•
FlexBus External Interface	•	•	•	•	•	•
USB 2.0 On-the-Go	•	•	•	•	•	•
UTMI+ Low Pin Interface (ULPI)	•	•	•	•	•	•
Synchronous Serial Interface (SSI)	•	•	•	•	•	•
Fast Ethernet Controller (FEC)	1	1	2	2	2	2
UARTs	3	3	3	3	3	3
I ² C	•	•	•	•	•	•
DSPI	•	•	•	•	•	•
Real Time Clock	•	•	•	•	•	•
32-bit DMA Timers	4	4	4	4	4	4
Watchdog Timer (WDT)	•	•	•	•	•	•
Periodic Interrupt Timers (PIT)	4	4	4	4	4	4
Edge Port Module (EPORT)	•	•	•	•	•	•
Interrupt Controllers (INTC)	2	2	2	2	2	2
16-channel Direct Memory Access (DMA)	•	•	•	•	•	•
General Purpose I/O (GPIO)	•	•	•	•	•	•
JTAG - IEEE® 1149.1 Test Access Port	•	•	•	•	•	•
Package	256 MAPBGA		360 TEPBGA			

2 Ordering Information

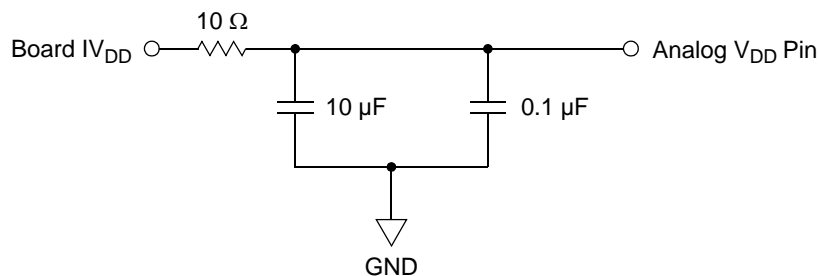
Table 2. Orderable Part Numbers

Freescale Part Number	Description	Package	Speed	Temperature
MCF54450CVM180	MCF54450 Microprocessor	256 MAPBGA	180 MHz	−40° to +85° C
MCF54450VM240			240 MHz	0° to +70° C
MCF54451CVM180	MCF54451 Microprocessor		180 MHz	−40° to +85° C
MCF54451VM240			240 MHz	0° to +70° C
MCF54452CVR200	MCF54452 Microprocessor	360 TEPBGA	200 MHz	−40° to +85° C
MCF54452YVR200			200 MHz	−40° to +105° C
MCF54452VR266			266 MHz	0° to +70° C
MCF54453CVR200	MCF54453 Microprocessor		200 MHz	−40° to +85° C
MCF54453VR266			266 MHz	0° to +70° C
MCF54454CVR200	MCF54454 Microprocessor		200 MHz	−40° to +85° C
MCF54454VR266			266 MHz	0° to +70° C
MCF54455CVR200	MCF54455 Microprocessor		200 MHz	−40° to +85° C
MCF54455VR266			266 MHz	0° to +70° C

3 Hardware Design Considerations

3.1 Analog Power Filtering

To further enhance noise isolation, an external filter is strongly recommended for the analog V_{DD} pins ($V_{DD_A_PLL}$, V_{DD_RTC}). The filter shown in Figure 2 should be connected between the board IV_{DD} and the analog pins. The resistor and capacitors should be placed as close to the dedicated analog V_{DD} pin as possible. The 10- Ω resistor in the given filter is required. Do not implement the filter circuit using only capacitors. The analog power pins draw very little current. Concerns regarding voltage loss across the 10-ohm resistor are not valid.


Figure 2. System Analog V_{DD} Power Filter

3.3.1 Power-Up Sequence

If EV_{DD}/SDV_{DD} are powered up with the IV_{DD} at 0 V, the sense circuits in the I/O pads cause all pad output drivers connected to the EV_{DD}/SDV_{DD} to be in a high impedance state. There is no limit on how long after EV_{DD}/SDV_{DD} powers up before IV_{DD} must power up. The rise times on the power supplies should be slower than 50 V/millisecond to avoid turning on the internal ESD protection clamp diodes.

3.3.2 Power-Down Sequence

If IV_{DD}/PV_{DD} are powered down first, sense circuits in the I/O pads cause all output drivers to be in a high impedance state. There is no limit on how long after IV_{DD} and PV_{DD} power down before EV_{DD} or SDV_{DD} must power down. There are no requirements for the fall times of the power supplies.

4 Pin Assignments and Reset States

4.1 Signal Multiplexing

The following table lists all the MCF5445x pins grouped by function. The Dir column is the direction for the primary function of the pin only. Refer to Section 4, “Pin Assignments and Reset States,” for package diagrams. For a more detailed discussion of the MCF5445x signals, consult the *MCF54455 Reference Manual* (MCF54455RM).

NOTE

In this table and throughout this document, a single signal within a group is designated without square brackets (i.e., $FB_AD[23]$), while designations for multiple signals within a group use brackets (i.e., $FB_AD[23:21]$) and is meant to include all signals within the two bracketed numbers when these numbers are separated by a colon.

NOTE

The primary functionality of a pin is not necessarily its default functionality. Most pins that are muxed with GPIO default to their GPIO functionality. See Table 3 for a list of the exceptions.

Table 3. Special-Case Default Signal Functionality

Pin	256 MAPBGA	360 TEPBGA
$FB_AD[31:0]$	$FB_AD[31:0]$ except when serial boot selects 0-bit boot port size.	
$FB_BE/BWE[3:0]$	$FB_BE/BWE[3:0]$	
$FB_CS[3:1]$	$FB_CS[3:1]$	
FB_OE	FB_OE	
FB_R/\overline{W}	FB_R/\overline{W}	
FB_TA	FB_TA	
FB_TS	FB_TS	

Table 3. Special-Case Default Signal Functionality (continued)

Pin	256 MAPBGA	360 TEPBGA
$\overline{\text{PCI_GNT}}[3:0]$	GPIO	$\overline{\text{PCI_GNT}}[3:0]$
$\overline{\text{PCI_REQ}}[3:0]$	GPIO	$\overline{\text{PCI_REQ}}[3:0]$
IRQ1	GPIO	$\overline{\text{PCI_INTA}}$ and configured as an agent.
ATA_RESET	GPIO	ATA reset

Table 4. MCF5445x Signal Information and Muxing

Signal Name	GPIO	Alternate 1	Alternate 2	Pull-up (U) ¹ Pull-down (D)	Direction ²	Voltage Domain	MCF54450 MCF54451 256 MAPBGA	MCF54452 MCF54453 MCF54454 MCF54455 360 TEPBGA
Reset								
$\overline{\text{RESET}}$	—	—	—	U	I	EVDD	L4	Y18
$\overline{\text{RSTOUT}}$	—	—	—	—	O	EVDD	M15	B17
Clock								
EXTAL/PCI_CLK	—	—	—	—	I	EVDD	M16	A16
XTAL	—	—	—	U ³	O	EVDD	L16	A17
Mode Selection								
BOOTMOD[1:0]	—	—	—	—	I	EVDD	M5, M7	AB17, AB21
FlexBus								
FB_AD[31:24]	PFBADH[7:0] ⁴	FB_D[31:24]	—	—	I/O	EVDD	A14, A13, D12, C12, B12, A12, D11, C11	J2, K4, J1, K1–3, L1, L4
FB_AD[23:16]	PFBADMH[7:0] ⁴	FB_D[23:16]	—	—	I/O	EVDD	B11, A11, D10, C10, B10, A10, D9, C9	L2, L3, M1–4, N1–2
FB_AD[15:8]	PFBADML[7:0] ⁴	FB_D[15:8]	—	—	I/O	EVDD	B9, A9, D8, C8, B8, A8, D7, C7	P1–2, R1–3, P4, T1–2
FB_AD[7:0]	PFBADL[7:0] ⁴	FB_D[7:0]	—	—	I/O	EVDD	B7, A7, D6, C6, B6, A6, D5, C5	T3–4, U1–3, V1–2, W1
$\overline{\text{FB_BE/BWE}}[3:2]$	PBE[3:2]	FB_TSI[1:0]	—	—	O	EVDD	B5, A5	Y1, W2
$\overline{\text{FB_BE/BWE}}[1:0]$	PBE[1:0]	—	—	—	O	EVDD	B4, A4	W3, Y2
FB_CLK	—	—	—	—	O	EVDD	B13	J3
$\overline{\text{FB_CS}}[3:1]$	PCS[3:1]	—	—	—	O	EVDD	C2, D4, C3	W5, AA4, AB3
$\overline{\text{FB_CS0}}$	—	—	—	—	O	EVDD	C4	Y4
$\overline{\text{FB_OE}}$	PFBCTL3	—	—	—	O	EVDD	A2	AA1
FB_R $\overline{\text{W}}$	PFBCTL2	—	—	—	O	EVDD	B2	AA3
$\overline{\text{FB_TA}}$	PFBCTL1	—	—	U	I	EVDD	B1	AB2

4.2 Pinout—256 MAPBGA

The pinout for the MCF54450 and MCF54451 packages are shown below.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16			
A		FB_OE	FB_TS	FB_BE/ BWE0	FB_BE/ BWE2	FB_AD 2	FB_AD 6	FB_AD 10	FB_AD 14	FB_AD 18	FB_AD 22	FB_AD 26	FB_AD 30	FB_AD 31	T0IN		A		
B	FB_TA	FB_R/W	USB_VBUS_ OC	FB_BE/ BWE1	FB_BE/ BWE3	FB_AD 3	FB_AD 7	FB_AD 11	FB_AD 15	FB_AD 19	FB_AD 23	FB_AD 27	FB_CLK	T1IN	FB_A 4	FB_A 6	B		
C	PST_DDATA2	FB_CS3	FB_CS1	FB_CS0	FB_AD 0	FB_AD 4	FB_AD 8	FB_AD 12	FB_AD 16	FB_AD 20	FB_AD 24	FB_AD 28	T3IN	FB_A 3	FB_A 5	FB_A 1	C		
D	PST_DDATA6	PST_DDATA3	PST_DDATA0	FB_CS2	FB_AD 1	FB_AD 5	FB_AD 9	FB_AD 13	FB_AD 17	FB_AD 21	FB_AD 25	FB_AD 29	T2IN	FB_A 0	FB_A 2	FB_A 7	D		
E	FEC0_COL	PST_DDATA7	PST_DDATA4	PST_DDATA1	USB_VBUS_ EN	IVDD	IVDD	IVDD	IVDD	IVDD	IVDD	IVDD	IVDD	FB_A 8	FB_A 9	FB_A 10	USB_DP	E	
F	FEC0_CRS	FEC0_MDIO	FEC0_MDC	PST_DDATA5	IVDD								IVDD	FB_A 11	FB_A 12	IRQ_1	USB_DM	F	
G	FEC0_RXCLK	FEC0_RXDV	FEC0_RXD3	FEC0_RXD2	EVDD								EVDD	FB_A 13	FB_A 14	FB_A 15	NC	G	
H	FEC0_RXD1	FEC0_RXD0	FEC0_RXER	FEC0_TXCLK	EVDD								EVDD	FB_A 18	FB_A 17	FB_A 16	XTAL 32K	H	
J	FEC0_TXD3	FEC0_TXD2	FEC0_TXD1	FEC0_TXD0	EVDD								EVDD	FB_A 19	FB_A 20	FB_A 21	EXTAL 32K	J	
K	FEC0_TXEN	FEC0_TXER	I2C_SCL	I2C_SDA	EVDD								EVDD	FB_A 22	FB_A 23	VDD_A _PLL	PLL TEST	K	
L	IRQ_7	IRQ_4	IRQ_3	RESET	EVDD	EVDD								EVDD	DSPI_PCS2	VDD_OSC	VSS_OSC	XTAL	L
M	U0TXD	U0RTS	U0CTS	SD_A7	BOOT MOD1	TEST	BOOT MOD0	SD_VREF				JTAG_EN	VDD_RTC	TRST	DACK1	RST_OUT	EXTAL	M	
N	U0RXD	SD_A11	SD_A6	SD_A0	SD_CKE	SD_D31	SD_D29	SD_D24	SD_D23	SD_D19	SD_DQS2	SD_DM2	DSPI_SOUT	DSPI_PCS5	DACK0	DREQ0	N		
P	SD_A12	SD_A10	SD_A5	SD_BA1	SD_RAS	SD_CS1	SD_D28	SD_D25	SD_DM3	SD_D20	SD_D16	SSI_FS	TCLK	DSPI_PCS1	DSPI_SIN	DREQ1	P		
R	SD_A13	SD_A9	SD_A4	SD_A1	SD_WE	SD_CS0	SD_D27	SD_D26	SD_DQS3	SD_D21	SD_D17	SSI_TXD	SSI_BCLK	TMS	DSPI_SCK	DSPI_PCS0	R		
T		SD_A8	SD_A3	SD_A2	SD_BA0	SD_CAS	SD_D30	SD_CLK	SD_CLK	SD_D22	SD_D18	SSI_RXD	SSI_MCLK	TDO	TDI		T		
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16			

Figure 5. MCF54450 and MCF54451 Pinout (256 MAPBGA)

4.3 Pinout—360 TEPBGA

The pinout for the MCF54452, MCF54453, MCF54454, and MCF54455 packages are shown below.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	
A		PCI_REQ0	PCI_AD10	PCI_AD11	PCI_AD13	PCI_SERR	PCI_STOP	PCI_AD15	PCI_GNT0	PCI_AD29	PCI_AD20	XTAL_32K	EXTAL_32K	USB_DM	USB_DP	EXTAL	XTAL	DACK0	DSPL_PCS2	DSPL_SCK	TDO		A
B	PCI_CBE0	PCI_FRAME	PCI_AD9	PCI_PERR	PCI_AD12	PCI_RST	PCI_GNT3	PCI_AD14	PCI_AD18	PCI_AD28	PCI_AD19	PCI_AD21	NC		NC	VDD_OSC	RST_OUT	DREQ0	DSPL_SIN	DSPL_PCS1	TMS	TRST	B
C	PCI_AD0	PCI_AD2	PCI_IRDY	PCI_PAR	PCI_REQ1	IRQ1	PCI_REQ3	PCI_GNT2	PCI_GNT1	PCI_TRDY	PCI_AD31	PCI_AD22	VDD_RTC	VDD_A_PLL	NC	VSS_OSC	DACK1	DREQ1	TDI	DSPL_SOUT	JTAG_EN	TCLK	C
D	PCI_CBE1	PCI_AD1	PCI_AD7	PCI_AD8	PCI_IDSEL	IVDD	PCI_REQ2	IVDD	PCI_AD17	PCI_AD16	PCI_AD30	PCI_AD23	EVDD	IVDD	PLL_TEST	NC	DSPL_PCS0	DSPL_PCS5	EVDD	SSL_MCLK	SSL_RXD	SSL_TXD	D
E	PCI_AD4	PCI_AD5	PCI_AD6	PCI_CBE2															SSL_BCLK	SSL_FS	SD_DM2	SD_DQS2	E
F	PCI_AD24	PCI_DE_VSEL	PCI_AD3	IVDD																SD_D16	SD_D17	SD_D18	F
G	T0IN	PCI_AD26	PCI_AD25	PCI_CBE3															SD_D19	SD_D20	SD_D21	SD_D22	G
H	T2IN	T3IN	T1IN	IVDD																SD_D23	SD_DM3	SD_DQS3	H
J	FB_AD_29	FB_AD_31	FB_CLK	PCI_AD27															SD_D26	SD_D27	SD_D25	SD_D24	J
K	FB_AD_28	FB_AD_27	FB_AD_26	FB_AD_30																SD_D28	SD_D29	SD_D30	K
L	FB_AD_25	FB_AD_23	FB_AD_22	FB_AD_24															SD_CAS	SD_CS1	SD_D31	SD_CLK	L
M	FB_AD_21	FB_AD_20	FB_AD_19	FB_AD_18																SD_CS0	SD_VREF	SD_CLK	M
N	FB_AD_17	FB_AD_16	U1TXD	IVDD															SD_A2	SD_WE	SD_RAS	SD_CKE	N
P	FB_AD_15	FB_AD_14	U1RXD	FB_AD_10															SD_BA0	SD_A1	SD_A0	SD_BA1	P
R	FB_AD_13	FB_AD_12	FB_AD_11	IVDD																SD_A5	SD_A4	SD_A3	R
T	FB_AD_9	FB_AD_8	FB_AD_7	FB_AD_6															SD_A9	SD_A8	SD_A7	SD_A6	T
U	FB_AD_5	FB_AD_4	FB_AD_3	U1RTS																SD_A12	SD_A11	SD_A10	U
V	FB_AD_2	FB_AD_1	U1CTS	USB_VBUS_OC															ATA_DA2	ATA_DA1	ATA_DA0	SD_A13	V
W	FB_AD_0	FB_BE/BWE2	FB_BE/BWE1	IVDD	FB_CS3	PST_DDATA4	IVDD	IVDD	FEC0_RXD1	FEC0_TXD3	FEC0_TXEN	IVDD	ATA_RESET	FEC1_RXCLK	U0TXD	IVDD	FEC1_RXER	FEC1_TXD2	IVDD	FEC1_MDC	ATA_CS1	ATA_CS0	W
Y	FB_BE/BWE3	FB_BE/BWE0	FB_TS	FB_CS0	PST_DDATA0	PST_DDATA3	FEC0_MDIO	FEC0_RXDV	FEC0_RXD2	FEC0_TXCLK	FEC0_TXD0	I2C_SDA	ATA_BUFFER_EN	ATA_IORDY	FEC1_RXD2	U0CTS	FEC1_RXD0	RESET	FEC1_TXD3	FEC1_TXD0	NC	FEC1_MDIO	Y
AA	FB_OE	USB_VBUS_EN	FB_R/W	FB_CS2	PST_DDATA2	PST_DDATA7	FEC0_CRS	FEC0_RXCLK	NC	FEC0_RXER	FEC0_TXD1	I2C_SCL	IRQ4	ATA_DMARQ	FEC1_RXDV	U0RTS	FEC1_RXD1	FEC1_CRS	FEC1_TXD1	NC	FEC1_TXEN	FEC1_TXER	AA
AB		FB_TA	FB_CS1	PST_DDATA1	PST_DDATA5	PST_DDATA6	FEC0_COL	FEC0_MDC	FEC0_RXD3	FEC0_RXD0	FEC0_TXD2	FEC0_TXER	IRQ7	IRQ3	FEC1_RXDV	U0RXD	BOOT_MOD1	FEC1_COL	FEC1_TXCLK	TEST	BOOT_MOD0		AB

Figure 6. MCF54452, MCF54453, MCF54454, and MCF54455 Pinout (360 TEPBGA)

5 Electrical Characteristics

This document contains electrical specification tables and reference timing diagrams for the MCF54455 microprocessor. This section contains detailed information on DC/AC electrical characteristics and AC timing specifications.

The electrical specifications are preliminary and from previous designs or design simulations. These specifications may not be fully tested or guaranteed at this early stage of the product life cycle. However, for production silicon, these specifications will be met. Finalized specifications will be published after complete characterization and device qualifications have been completed.

NOTE

The parameters specified in this MCU document supersede any values found in the module specifications.

5.1 Absolute Maximum Ratings

Table 5. Absolute Maximum Ratings^{1, 2}

Rating	Symbol	Pin Name	Value	Units
External I/O pad supply voltage	EV _{DD}	EVDD	-0.3 to +4.0	V
Internal oscillator supply voltage	OSCV _{DD}	VDD_OSC	-0.3 to +4.0	V
Real-time clock supply voltage	RTCV _{DD}	VDD_RTC	-0.5 to +2.0	V
Internal logic supply voltage	IV _{DD}	IVDD	-0.5 to +2.0	V
SDRAM I/O pad supply voltage	SDV _{DD}	SD_VDD	-0.3 to +4.0	V
PLL supply voltage	PV _{DD}	VDD_A_PLL	-0.5 to +2.0	V
Digital input voltage ³	V _{IN}	—	-0.3 to +3.6	V
Instantaneous maximum current Single pin limit (applies to all pins) ^{3, 4, 5}	I _{DD}	—	25	mA
Operating temperature range (packaged)	T _A (T _L - T _H)	—	-40 to +85	°C
Storage temperature range	T _{stg}	—	-55 to +150	°C

¹ Functional operating conditions are given in Table 8. Absolute maximum ratings are stress ratings only, and functional operation at the maximum is not guaranteed. Continued operation at these levels may affect device reliability or cause permanent damage to the device.

² This device contains circuitry protecting against damage due to high static voltage or electrical fields. However, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (e.g., V_{SS} or EV_{DD}).

³ Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, and then use the larger of the two values.

⁴ All functional non-supply pins are internally clamped to V_{SS} and EV_{DD}.

⁵ Power supply must maintain regulation within operating EV_{DD} range during instantaneous and operating maximum current conditions. If positive injection current (V_{in} > EV_{DD}) is greater than I_{DD}, the injection current may flow out of EV_{DD} and could result in external power supply going out of regulation. Ensure the external EV_{DD} load shunts current greater than maximum injection current. This is the greatest risk when the MPU is not consuming power (ex; no clock). The power supply must maintain regulation within operating EV_{DD} range during instantaneous and operating maximum current conditions.

where K is a constant pertaining to the particular part. K can be determined from Equation 3 by measuring P_D (at equilibrium) for a known T_A . Using this value of K , the values of P_D and T_J can be obtained by solving Equation 1 and Equation 2 iteratively for any value of T_A .

5.3 ESD Protection

Table 7. ESD Protection Characteristics^{1, 2}

Characteristics	Symbol	Value	Units
ESD Target for Human Body Model	HBM	2000	V

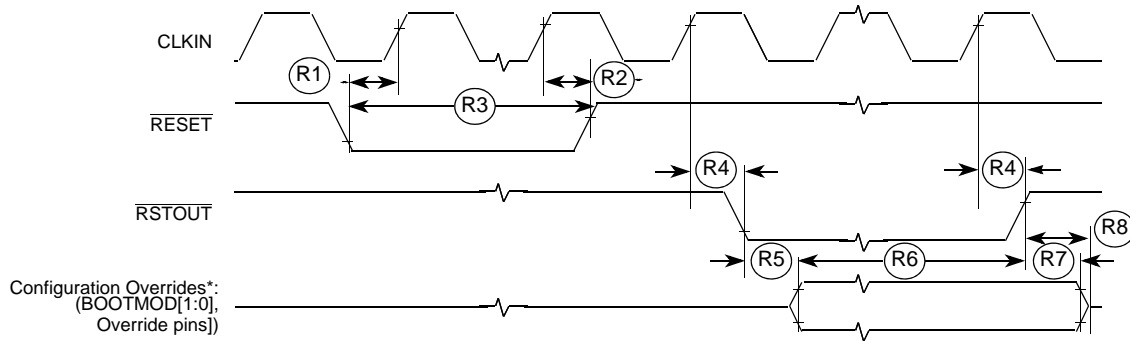
¹ All ESD testing is in conformity with CDF-AEC-Q100 Stress Test Qualification for Automotive Grade Integrated Circuits.

² A device is defined as a failure if after exposure to ESD pulses the device no longer meets the device specification requirements. Complete DC parametric and functional testing is performed per applicable device specification at room temperature followed by hot temperature, unless specified otherwise in the device specification.

5.4 DC Electrical Specifications

Table 8. DC Electrical Specifications

Characteristic	Symbol	Min	Max	Units
Internal logic supply voltage ¹	IV_{DD}	1.35	1.65	V
PLL analog operation voltage range ¹	PV_{DD}	1.35	1.65	V
External I/O pad supply voltage	EV_{DD}	3.0	3.6	V
Internal oscillator supply voltage	$OSCV_{DD}$	3.0	3.6	V
Real-time clock supply voltage	$RTCV_{DD}$	1.35	1.65	V
SDRAM I/O pad supply voltage — DDR mode	SDV_{DD}	2.25	2.75	V
SDRAM I/O pad supply voltage — DDR2 mode	SDV_{DD}	1.7	1.9	V
SDRAM I/O pad supply voltage — Mobile DDR mode	SDV_{DD}	1.7	1.9	V
SDRAM input reference voltage	SDV_{REF}	$0.49 \times SDV_{DD}$	$0.51 \times SDV_{DD}$	V
Input High Voltage	V_{IH}	$0.7 \times EV_{DD}$	3.65	V
Input Low Voltage	V_{IL}	$V_{SS} - 0.3$	$0.35 \times EV_{DD}$	V
Input Hysteresis	V_{HYS}	$0.06 \times EV_{DD}$	—	mV
Input Leakage Current ² $V_{in} = V_{DD}$ or V_{SS} , Input-only pins	I_{in}	-2.5	2.5	μA
Input Leakage Current ³ $V_{in} = V_{DD}$ or V_{SS} , Input-only pins	I_{in}	-5	5	μA
High Impedance (Off-State) Leakage Current ⁴ $V_{in} = V_{DD}$ or V_{SS} , All input/output and output pins	I_{OZ}	-10.0	10.0	μA
Output High Voltage (All input/output and all output pins) $I_{OH} = -5.0$ mA	V_{OH}	$0.85 \times EV_{DD}$	—	V
Output Low Voltage (All input/output and all output pins) $I_{OL} = 5.0$ mA	V_{OL}	—	$0.15 \times EV_{DD}$	V


Figure 8. $\overline{\text{RESET}}$ and Configuration Override Timing

5.7 FlexBus Timing Specifications

A multi-function external bus interface called FlexBus is provided with basic functionality to interface to slave-only devices up to a maximum bus frequency of 66MHz. It can be directly connected to asynchronous or synchronous devices such as external boot ROMs, flash memories, gate-array logic, or other simple target (slave) devices with little or no additional circuitry. For asynchronous devices, a simple chip-select based interface can be used.

All processor bus timings are synchronous; input setup/hold and output delay are given in respect to the rising edge of a reference clock, FB_CLK. The FB_CLK frequency may be the same as the internal system bus frequency or an integer divider of that frequency.

The following timing numbers indicate when data is latched or driven onto the external bus, relative to the Flexbus output clock (FB_CLK). All other timing relationships can be derived from these values.

Table 12. FlexBus AC Timing Specifications

Num	Characteristic	Min	Max	Unit	Notes
	Frequency of Operation	25	66.66	MHz	
FB1	Clock Period	15	40	ns	
FB2	Output Valid	—	7.0	ns	¹
FB3	Output Hold	1.0	—	ns	1
FB4	Input Setup	3.0	—	ns	²
FB5	Input Hold	0	—	ns	2

¹ Specification is valid for all FB_AD[31:0], FB_BS[3:0], FB_CS[3:0], FB_OE, FB_R/W, FB_TBST, FB_TSI[1:0], and FB_TS.

² Specification is valid for all FB_AD[31:0] and FB_TA.

NOTE

The processor drives the data lines during the first clock cycle of the transfer with the full 32-bit address. This may be ignored by standard connected devices using non-multiplexed address and data buses. However, some applications may find this feature beneficial.

The address and data busses are muxed between the FlexBus and PCI controller. At the end of the read and write bus cycles the address signals are indeterminate.

5.8 SDRAM AC Timing Characteristics

The following timing numbers must be followed to properly latch or drive data onto the SDRAM memory bus. All timing numbers are relative to the four DQS byte lanes.

Table 13. SDRAM Timing Specifications

Num	Characteristic	Symbol	Min	Max	Unit	Notes
	Frequency of Operation		60	133.33	MHz	¹
DD1	Clock Period	t_{SDCK}	7.5	16.67	ns	
DD2	Pulse Width High	t_{SDCKH}	0.45	0.55	t_{SDCK}	²
DD3	Pulse Width Low	t_{SDCKL}	0.45	0.55	t_{SDCK}	³
DD4	Address, $\overline{SD_CKE}$, $\overline{SD_CAS}$, $\overline{SD_RAS}$, $\overline{SD_WE}$, $\overline{SD_CS}[1:0]$ — Output Valid	t_{CMV}	—	$(0.5 \times t_{SDCK}) + 1.0\text{ns}$	ns	³
DD5	Address, $\overline{SD_CKE}$, $\overline{SD_CAS}$, $\overline{SD_RAS}$, $\overline{SD_WE}$, $\overline{SD_CS}[1:0]$ — Output Hold	t_{CMH}	2.0	—	ns	
DD6	Write Command to first DQS Latching Transition	t_{DQSS}	$(1.0 \times t_{SDCK}) - 0.6\text{ns}$	$(1.0 \times t_{SDCK}) + 0.6\text{ns}$	ns	
DD7	Data and Data Mask Output Setup (DQ-->DQS) Relative to DQS (DDR Write Mode)	t_{QS}	1.0	—	ns	⁴ ⁵
DD8	Data and Data Mask Output Hold (DQS-->DQ) Relative to DQS (DDR Write Mode)	t_{QH}	1.0	—	ns	⁶
DD9	Input Data Skew Relative to DQS (Input Setup)	t_{IS}	—	1.0	ns	⁷
DD10	Input Data Hold Relative to DQS.	t_{IH}	$(0.25 \times t_{SDCK}) + 0.5\text{ns}$	—	ns	⁸

¹ The SDRAM interface operates at the same frequency as the internal system bus.

² Pulse width high plus pulse width low cannot exceed min and max clock period.

³ Command output valid should be 1/2 the memory bus clock (t_{SDCK}) plus some minor adjustments for process, temperature, and voltage variations.

⁴ This specification relates to the required input setup time of DDR memories. The microprocessor's output setup should be larger than the input setup of the DDR memories. If it is not larger, then the input setup on the memory is in violation.
SD_D[31:24] is relative to SD_DQS[3]; SD_D[23:16] is relative to SD_DQS[2]

⁵ The first data beat is valid before the first rising edge of DQS and after the DQS write preamble. The remaining data beats are valid for each subsequent DQS edge.

⁶ This specification relates to the required hold time of DDR memories.
SD_D[31:24] is relative to SD_DQS[3]; SD_D[23:16] is relative to SD_DQS[2]

⁷ Data input skew is derived from each DQS clock edge. It begins with a DQS transition and ends when the last data line becomes valid. This input skew must include DDR memory output skew and system level board skew (due to routing or other factors).

⁸ Data input hold is derived from each DQS clock edge. It begins with a DQS transition and ends when the first data line becomes invalid.

Table 14. PCI Timing Specifications^{1,2} (continued)

Num	Characteristic	33 MHz ³		66 MHz ³		Unit
		Min	Max	Min	Max	
P6	PCI_REQ[3:0]/PCI_GNT[3:0] — output valid	—	12.0	—	6.0	ns
P7	All PCI signals — output hold	2.0	—	1.0	—	ns

- ¹ The PCI bus operates at the CLKIN frequency. All timings are relative to the input clock, CLKIN.
- ² All PCI signals are bused signals except for PCI_GNT[3:0] and PCI_REQ[3:0]. These signals are defined as point-to-point signals by the PCI Specification.
- ³ The 66-MHz parameters are only guaranteed when the 66-MHz PCI pad slew rates are selected. Likewise, the 33-MHz parameters are only guaranteed when the 33-MHz PCI pad slew rates are selected.

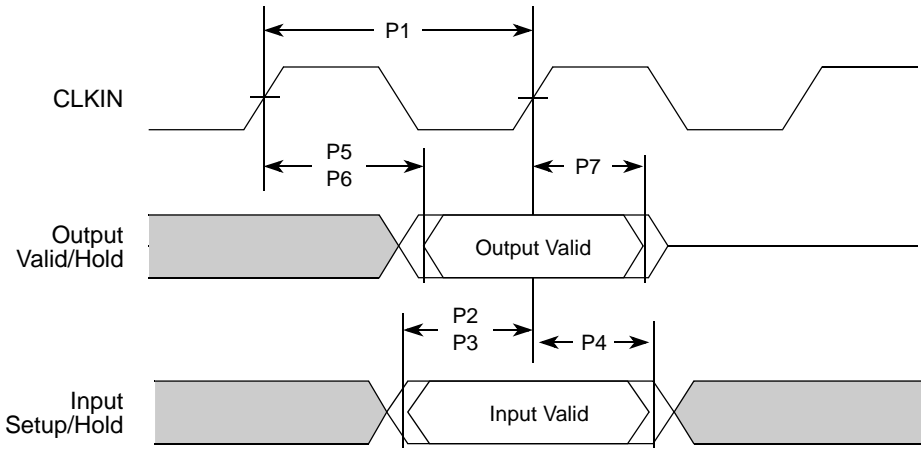


Figure 13. PCI Timing

5.9.1 Overshoot and Undershoot

Figure 14 shows the specification limits for overshoot and undershoot for PCI I/O. To guarantee long term reliability, the specification limits shown must be followed. Good transmission line design practices should be observed to guarantee the specification limits.

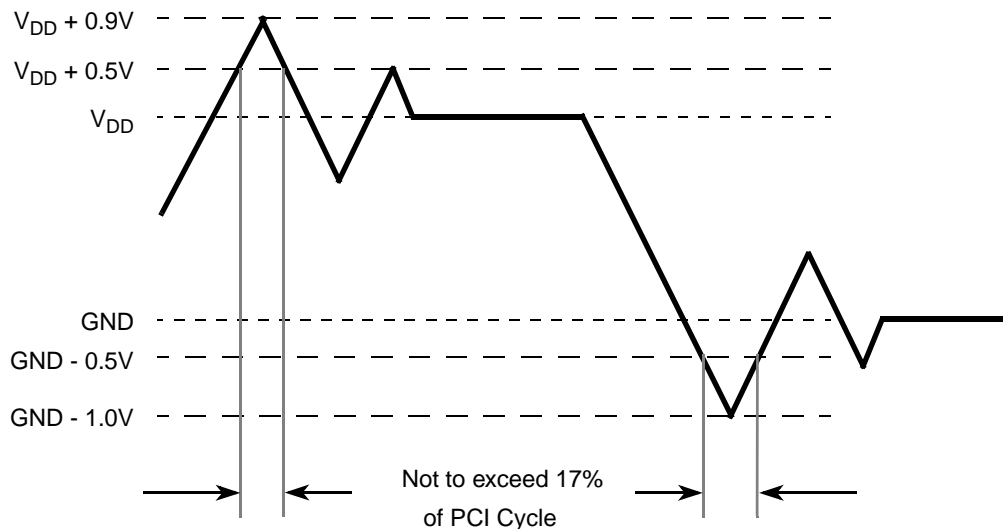


Figure 14. Overshoot and Undershoot Limits

5.10 ULPI Timing Specifications

The ULPI interface is fully compliant with the industry standard UTMI+ Low Pin Interface. Control and data timing requirements for the ULPI pins are given in Table 15. These timings apply to synchronous mode only. All timings are measured with respect to the clock as seen at the USB_CLKIN pin on the MCF5445x. The ULPI PHY is the source of the 60MHz clock.

NOTE

The USB controller requires a 60-MHz clock, even if using the on-chip FS/LS transceiver instead of the ULPI interface. In this case, the 60-MHz clock can be generated by the PLL or input on the USB_CLKIN pin.

Table 15. ULPI Interface Timing

Num	Characteristic	Min	Nominal	Max	Units
	USB_CLKIN operating frequency	—	60	—	MHz
	USB_CLKIN duty cycle	—	50	—	%
U1	USB_CLKIN clock period	—	16.67	—	ns
U2	Input Setup (control and data)	5.0	—	—	ns
U3	Input Hold (control and data)	1.0	—	—	ns
U4	Output Valid (control and data)	—	—	9.5	ns
U5	Output Hold (control and data)	1.0	—	—	

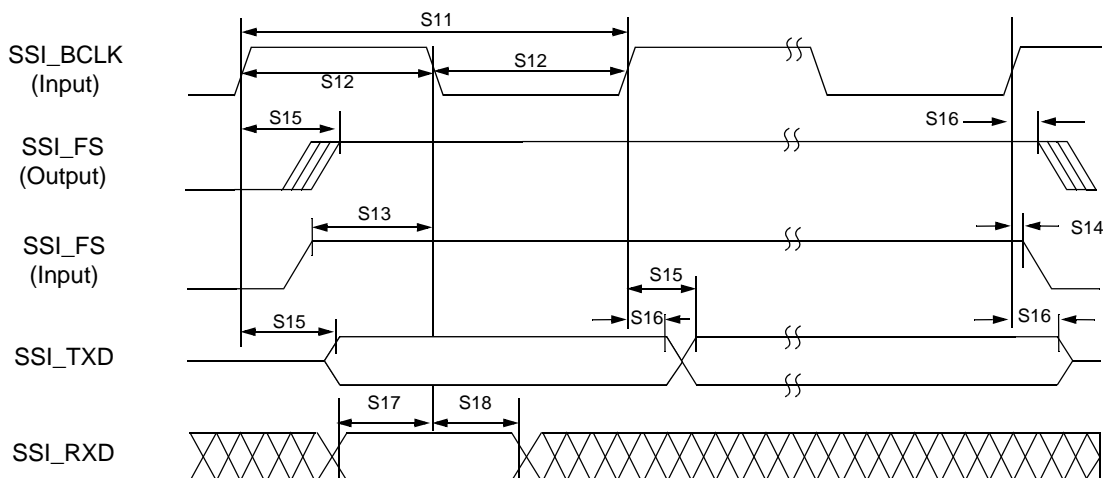


Figure 17. SSI Timing—Slave Modes

5.12 I²C Timing Specifications

Table 18 lists specifications for the I²C input timing parameters shown in Figure 18.

Table 18. I²C Input Timing Specifications between SCL and SDA

Num	Characteristic	Min	Max	Units
I1	Start condition hold time	2	—	t _{sys}
I2	Clock low period	8	—	t _{sys}
I3	I2C_SCL/I2C_SDA rise time (V _{IL} = 0.5 V to V _{IH} = 2.4 V)	—	1	ms
I4	Data hold time	0	—	ns
I5	I2C_SCL/I2C_SDA fall time (V _{IH} = 2.4 V to V _{IL} = 0.5 V)	—	1	ms
I6	Clock high time	4	—	t _{sys}
I7	Data setup time	0	—	ns
I8	Start condition setup time (for repeated start condition only)	2	—	t _{sys}
I9	Stop condition setup time	2	—	t _{sys}

Table 19 lists specifications for the I²C output timing parameters shown in Figure 18.

Table 19. I²C Output Timing Specifications between SCL and SDA

Num	Characteristic	Min	Max	Units
I1 ¹	Start condition hold time	6	—	t _{sys}
I2 ¹	Clock low period	10	—	t _{sys}
I3 ²	I2C_SCL/I2C_SDA rise time (V _{IL} = 0.5 V to V _{IH} = 2.4 V)	—	—	μs
I4 ¹	Data hold time	7	—	t _{sys}
I5 ³	I2C_SCL/I2C_SDA fall time (V _{IH} = 2.4 V to V _{IL} = 0.5 V)	—	3	ns

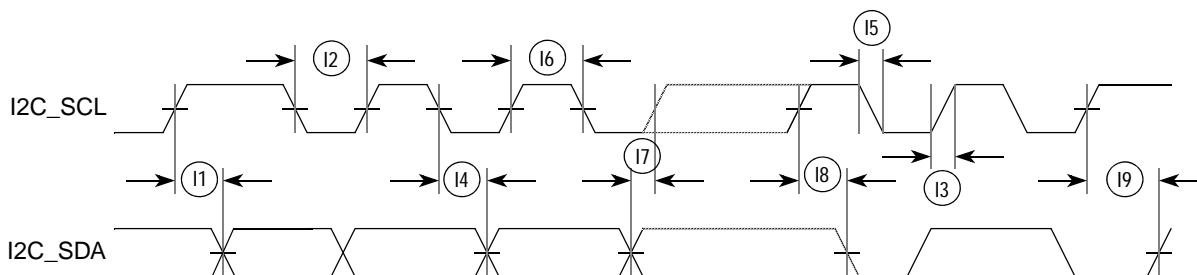
Table 19. I²C Output Timing Specifications between SCL and SDA (continued)

Num	Characteristic	Min	Max	Units
I6 ¹	Clock high time	10	—	t _{SYS}
I7 ¹	Data setup time	2	—	t _{SYS}
I8 ¹	Start condition setup time (for repeated start condition only)	20	—	t _{SYS}
I9 ¹	Stop condition setup time	10	—	t _{SYS}

¹ Output numbers depend on the value programmed into the IFDR; an IFDR programmed with the maximum frequency (IFDR = 0x20) results in minimum output timings as shown in Table 19. The I²C interface is designed to scale the actual data transition time to move it to the middle of the SCL low period. The actual position is affected by the prescale and division values programmed into the IFDR. However, the numbers given in Table 19 are minimum values.

² Because I2C_SCL and I2C_SDA are open-collector-type outputs, which the processor can only actively drive low, the time I2C_SCL or I2C_SDA take to reach a high level depends on external signal capacitance and pull-up resistor values.

³ Specified at a nominal 50-pF load.


Figure 18. I²C Input/Output Timings

5.13 Fast Ethernet Timing Specifications

The following timing specs are defined at the chip I/O pin and must be translated appropriately to arrive at timing specs/constraints for the physical interface.

5.13.1 Receive Signal Timing Specifications

The following timing specs meet the requirements for MII and 7-Wire style interfaces for a range of transceiver devices.

Table 20. Receive Signal Timing

Num	Characteristic	MII Mode		RMII Mode		Unit
		Min	Max	Min	Max	
—	RXCLK frequency	—	25	—	50	MHz
E1	RXD[n:0], RXDV, RXER to RXCLK setup ¹	5	—	4	—	ns
E2	RXCLK to RXD[n:0], RXDV, RXER hold ¹	5	—	2	—	ns
E3	RXCLK pulse width high	35%	65%	35%	65%	RXCLK period
E4	RXCLK pulse width low	35%	65%	35%	65%	RXCLK period

¹ In MII mode, n = 3; In RMII mode, n = 1

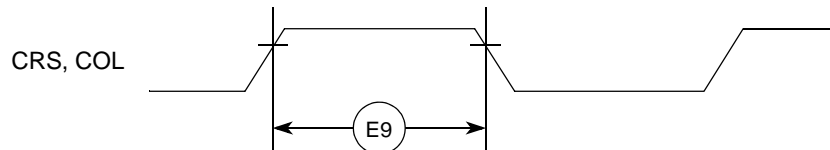


Figure 21. MII Async Inputs Timing Diagram

5.13.4 MII Serial Management Timing Specifications

Table 23. MII Serial Management Channel Signal Timing

Num	Characteristic	Symbol	Min	Max	Unit
E10	MDC cycle time	t_{MDC}	400	—	ns
E11	MDC pulse width		40	60	% t_{MDC}
E12	MDC to MDIO output valid		—	375	ns
E13	MDC to MDIO output invalid		25	—	ns
E14	MDIO input to MDC setup		10	—	ns
E15	MDIO input to MDC hold		0	—	ns

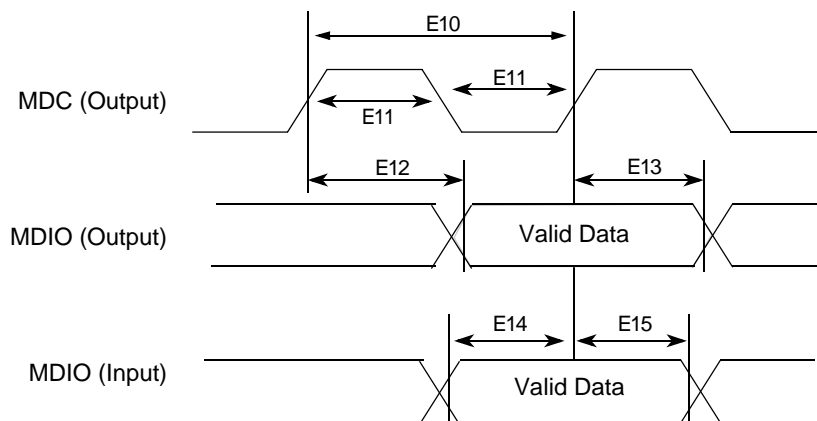


Figure 22. MII Serial Management Channel Timing Diagram

5.14 32-Bit Timer Module Timing Specifications

Table 24 lists timer module AC timings.

Table 24. Timer Module AC Timing Specifications

Name	Characteristic	Min	Max	Unit
T1	DTnIN cycle time ($n = 0:3$)	3	—	$t_{sys}/2$
T2	DTnIN pulse width ($n = 0:3$)	1	—	$t_{sys}/2$

Table 26. DSPI Module AC Timing Specifications¹ (continued)

Name	Characteristic	Symbol	Min	Max	Unit	Notes
DS10	DSPI_SCK to DSPI_SOUT invalid	—	0	—	ns	
DS11	DSPI_SIN to DSPI_SCK input setup	—	2	—	ns	
DS12	DSPI_SCK to DSPI_SIN input hold	—	7	—	ns	
DS13	$\overline{\text{DSPI_SS}}$ active to DSPI_SOUT driven	—	—	10	ns	
DS14	$\overline{\text{DSPI_SS}}$ inactive to DSPI_SOUT not driven	—	—	10	ns	

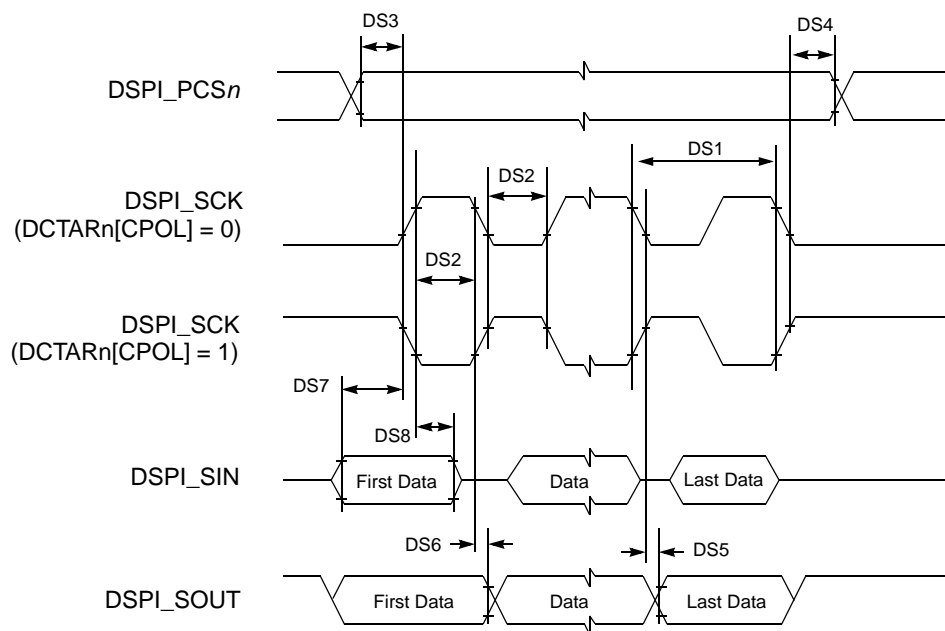
¹ Timings shown are for DMCR[MTFE] = 0 (classic SPI) and DCTAR_n[CPHA] = 0. Data is sampled on the DSPI_SIN pin on the odd-numbered DSPI_SCK edges and driven on the DSPI_SOUT pin on even-numbered DSPI edges.

² When in master mode, the baud rate is programmable in DCTAR_n[DBR], DCTAR_n[PBR], and DCTAR_n[BR].

³ This specification assumes a 50/50 duty cycle setting. The duty cycle is programmable in DCTAR_n[DBR], DCTAR_n[CPHA], and DCTAR_n[PBR].

⁴ The DSPI_PCS_n to DSPI_SCK delay is programmable in DCTAR_n[PCSSCK] and DCTAR_n[CSSCK].

⁵ The DSPI_SCK to DSPI_PCS_n delay is programmable in DCTAR_n[PASC] and DCTAR_n[ASC].


Figure 23. DSPI Classic SPI Timing—Master Mode

5.19 JTAG and Boundary Scan Timing

Table 29. JTAG and Boundary Scan Timing

Num	Characteristics ¹	Min	Max	Unit
J1	TCLK Frequency of Operation	DC	20	MHz
J2	TCLK Cycle Period	50	—	ns
J3	TCLK Clock Pulse Width	20	30	ns
J4	TCLK Rise and Fall Times	—	3	ns
J5	Boundary Scan Input Data Setup Time to TCLK Rise	5	—	ns
J6	Boundary Scan Input Data Hold Time after TCLK Rise	20	—	ns
J7	TCLK Low to Boundary Scan Output Data Valid	—	33	ns
J8	TCLK Low to Boundary Scan Output High Z	—	33	ns
J9	TMS, TDI Input Data Setup Time to TCLK Rise	4	—	ns
J10	TMS, TDI Input Data Hold Time after TCLK Rise	10	—	ns
J11	TCLK Low to TDO Data Valid	—	11	ns
J12	TCLK Low to TDO High Z	—	11	ns
J13	$\overline{\text{TRST}}$ Assert Time	50	—	ns
J14	$\overline{\text{TRST}}$ Setup Time (Negation) to TCLK High	10	—	ns

¹ JTAG_EN is expected to be a static signal. Hence, specific timing is not associated with it.

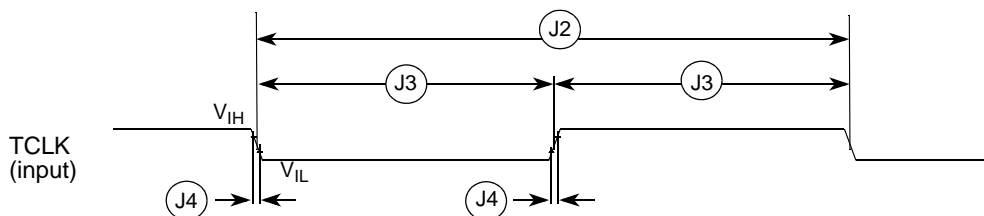


Figure 27. Test Clock Input Timing

6 Power Consumption

All power consumption data is lab data measured on an M54455EVB running the Freescale Linux BSP.

Table 31. MCF4455 Application Power Consumption¹

Core Freq.		Idle	MP3 Playback	TFTP Download	USB HS File Copy	Units
266 MHz	IV _{DD}	215.6	288.8	274.4	263.7	mA
	EV _{DD}	27.6	33.6	32.6	32.4	
	SDV _{DD}	142.9	158.2	161.1	158.0	
	Total Power	672	829	809	787	mW
200 MHz	IV _{DD}	163.8	228.0	213.8	207.9	mA
	EV _{DD}	29.9	34.7	34.3	33.8	
	SDV _{DD}	142.2	158.5	160.0	153.4	
	Total Power	601	742	722	699	mW

¹ All voltage rails at nominal values: IV_{DD} = 1.5 V, EV_{DD} = 3.3 V, and SDV_{DD} = 1.8 V.

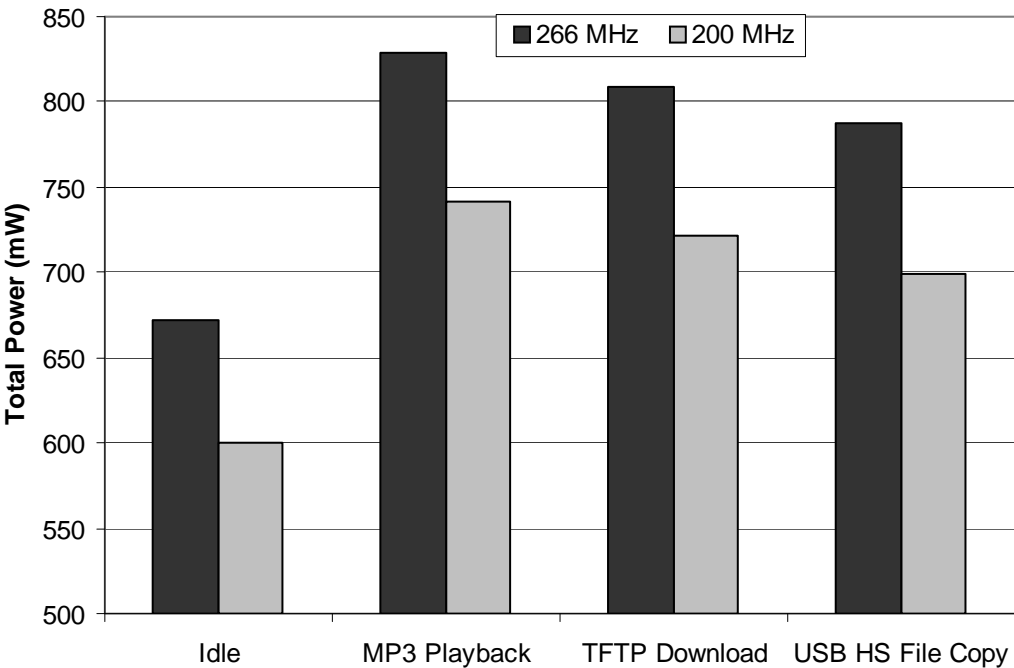


Figure 33. Power Consumption in Various Applications

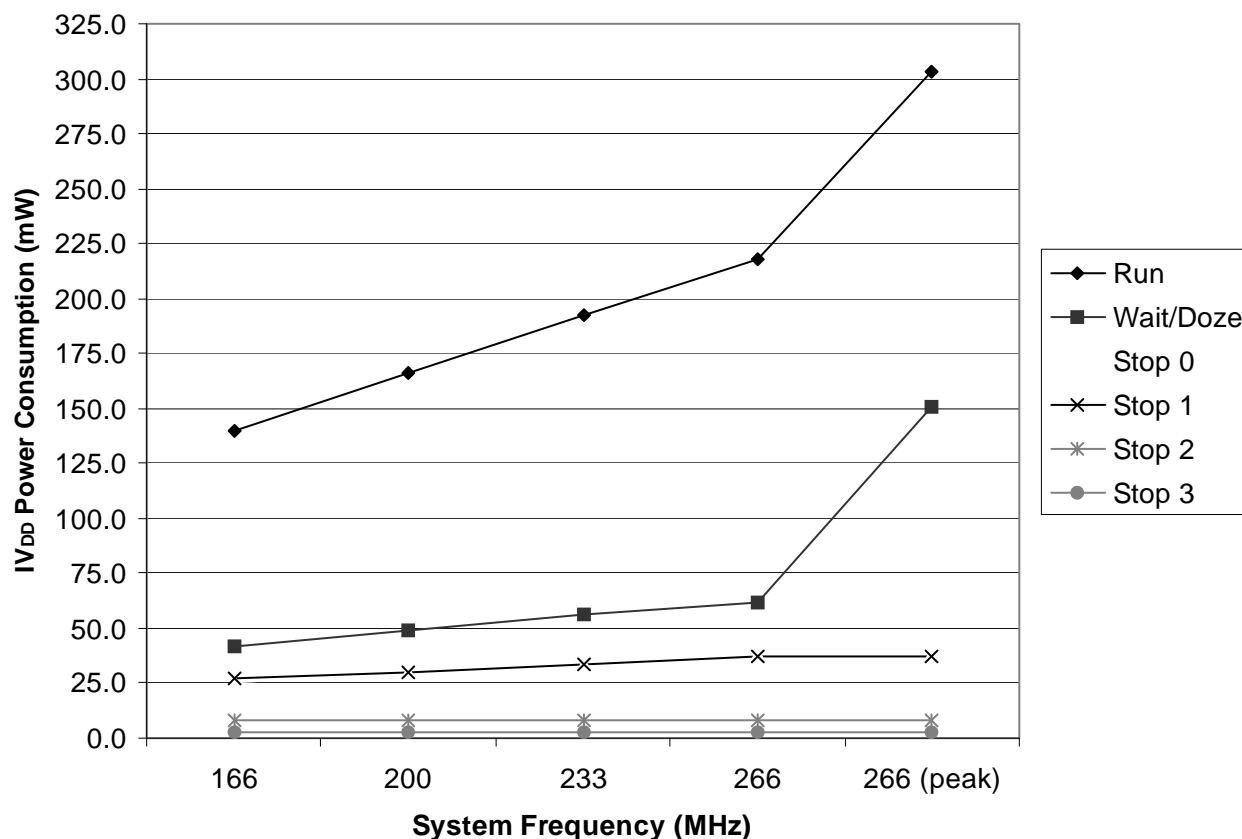


Figure 34. IV_{DD} Power Consumption in Low-Power Modes

7 Package Information

The latest package outline drawings are available on the product summary pages on <http://www.freescale.com/coldfire>.

Table 33 lists the case outline numbers per device. Use these numbers in the web page's keyword search engine to find the latest package outline drawings.

Table 33. Package Information

Device	Package Type	Case Outline Numbers
MCF54450	256 MAPBGA	98ARH98219A
MCF54451		
MCF54452	360 TEPBGA	98ARE10605D
MCF54453		
MCF54454		
MCF54455		

8 Product Documentation

Documentation is available from a local Freescale distributor, a Freescale sales office, the Freescale Literature Distribution Center, or through the Freescale world-wide web address at <http://www.freescale.com/coldfire>.

9 Revision History

Table 34 summarizes revisions to this document.

Table 34. Revision History

Rev. No.	Date	Summary of Changes
0	Sept 17, 2007	Initial public release.
1	Feb 15, 2008	Corrected VSS pin locations in MCF5445x signal information and muxing table for the 360 TEPBGA package: changed "...M9, M16, M17..." to "...M9–M14, M16..." Updated FlexBus read and write timing diagrams and added two notes before them. Change FB_A[23:0] to FB_A[31:0] in FlexBus read and write timing diagrams. Added power consumption section.
2	May 1, 2008	In Family Configurations table, added PCI as feature on 256-pin devices. On these devices the PCI_AD bus is limited to 24-bits. In Absolute Maximum Ratings table, changed RTCV _{DD} specification from "–0.3 to +4.0" to "–0.5 to +2.0". In DC Electrical Specifications table: <ul style="list-style-type: none"> Changed RTCV_{DD} specification from 3.0–3.6 to 1.35–1.65. Changed High Impedance (Off-State) Leakage Current (I_{OZ}) specification from ±1 to ±10μA, and added footnote to this spec: "Worst-case tristate leakage current with only one I/O pin high. Since all I/Os share power when high, the leakage current is distributed among them. With all I/Os high, this spec reduces to ±2 μA min/max."
3	Dec 1, 2008	Changed "360PBGA" heading to "360 TEPBGA" in Table 6. Changed the following specs in Table 13: <ul style="list-style-type: none"> Minimum frequency of operation from — to 60MHz. Maximum clock period from — to 16.67 ns.
4	Apr 12, 2009	Rescinded previous errata, the 256-pin devices do not contain the PCI bus controller: <ul style="list-style-type: none"> In Table 4, in PCI_AD_n signal section, added a separate row for each package, with PCI_AD_n signals shown as — for 256-pin devices. In Figure 5, changed the PCI_AD_n pins to their alternative function, FB_An.
5	Apr 27, 2009	In Table 2 changed MCF54450VM180 to MCF54450CVM180 and changed its temperature entry from "0° to +70° C" to "–40° to +85° C".
6	Oct 15, 2009	In Table 8 changed Input Leakage Current (I _{in}) from ±1.0 to ±2.5μA.
7	Oct 18, 2011	In Table 2, added MCF54452YVR200 part number, with temperature range from –40° to +105° C. In Table 8, added Input Leakage Current (I _{in}) values for MCF54452YVR200 part number.
8	Jan 18, 2012	In Table 4, added pin N7 in the VSS pin list for the 360 TEPBGA.